

ELECTRONIC INFORMATION DISCLOSURE STATEMENT

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Title of Invention	APPLYING PARAMETRIC TEST PATTERNS FOR HIGH PIN COUNT ASICs ON LOW PIN COUNT TESTERS
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Application Number :

Confirmation Number:

First Named Applicant: Dennis Conti

Attorney Docket Number: BUR920020113US1

Art Unit:

Examiner:

Search string: (5973504 or 6192496 or 6247155 or 6348789 or 6446228 or 3922537 or 4094568 or 4884287 or 4939454 or 5000692 or 5450017 or 5754823 or 5898314 or 5909450 or 5936415 or 5952839).pn

US Patent Documents

Note: Applicant is not required to submit a paper copy of cited US Patent Documents

init	Cite.No.	Patent No.	Date	Patentee	Kind	Class	Subclass
	1	5973504	1999-10-26	Chong			
	2	6192496	2001-02-20	Lawrence et al.			
	3	6247155	2001-06-12	Wright			
	4	6348789	2002-02-19	Terao			
	5	6446228	2002-09-03	Kobayashi			
	6	3922537	1975-11-25	Jackson			
	7	4094568	1978-06-13	Lee et al.			
	8	4884287	1989-11-28	Jones et al.			
	9	4939454	1990-07-03	Miner			
	10	5000692	1991-03-19	Taniguchi et al.			
	11	5450017	1995-09-12	Swart			
	12	5754823	1998-05-19	Mudryk, Jr. et al.			
	13	5898314	1999-04-27	Swart			
	14	5909450	1999-06-01	Wright			
	15	5936415	1999-08-10	Fredrickson			
	16	5952839	1999-09-14	Fredrickson			

Signature

Examiner Name	Date